

## Security and Privacy Concerns for the FPGA-Accelerated Cloud and Datacenters

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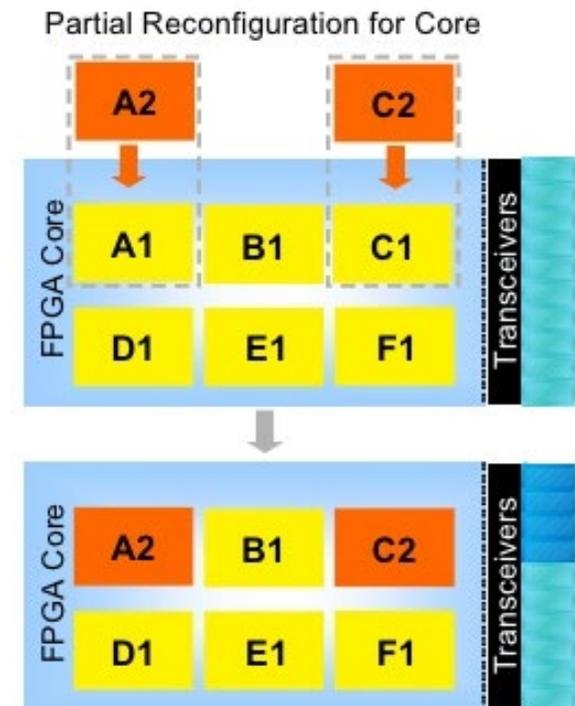
# Overview

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- Background
  - FPGAs in the cloud
  - Multi-tenant FPGAs
  - FPGA voltage attack approaches
  
- Characterizing voltage attacks on Arria 10
  - Experimental approach
  - Characterization test results
  - Fault induction
  
- RSA attack using power fluctuation on Cyclone V and Arria 10
  - Induce delay faults in RSA
  - Use Chinese remainder theorem to extract key

# Multi-Tenant FPGA

- Shared (multi-tenant) FPGAs
  - Devices are expensive. Desire to fully use resources
- Cloud computing: target for multi-tenant FPGAs?
  - Why not use partial reconfiguration?
  - User has no idea what “neighbor” is doing (side channels)
  - Don’t want to risk leaking information
- Need to understand vulnerabilities
  - Previous: temperature, voltage
  - This work: no physical access needed

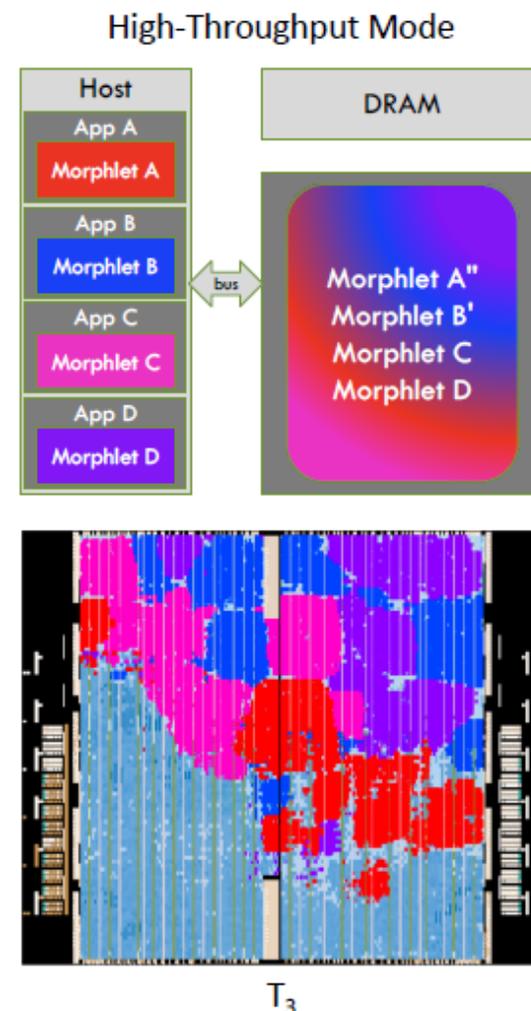


Source: Intel<sup>1</sup>

<sup>1</sup> Stratix V FPGAs: Built for Bandwidth, Intel Corporation, 2010  
Department of Electrical and Computer Engineering

## Example: AmorphOS for Amazon EC2 F1

- Multiple users deploy circuits (Morphlets) on FPGA
- Virtualizing software multiplexing software and memory interfaces
- Attempt to create “virtual machine” like environment on the FPGA
- Increase income level for hardware use.
- **Security?: not really a focus**

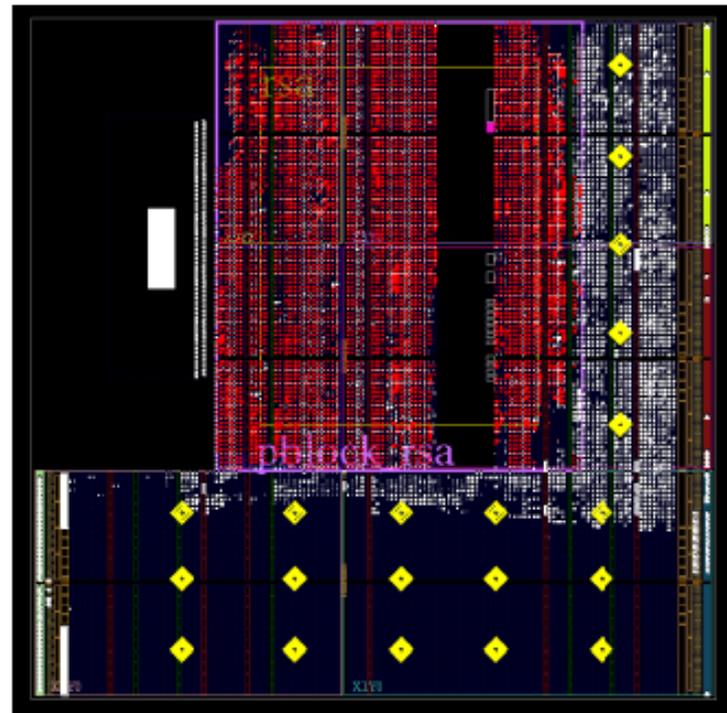


Source: Khawaja et al<sup>1</sup>

<sup>1</sup> A. Khawaja et al., Sharing, Protection, and Compatibility for Reconfigurable Fabric with AmorphoS, OSDI, Oct. 2018  
Department of Electrical and Computer Engineering

# What Type of FPGA Voltage Attacks are Possible?

- On-chip voltage sensors to extract encryption key
  - Ring oscillators used to extract RSA key<sup>1</sup>
  - Time-to-digital converters used to extract AES key<sup>2</sup>
- Voltage fluctuation-based communication
  - Communication on single FPGA<sup>3,4</sup>
- On-chip voltage supply attacks
  - Induce stealthy faults<sup>5, 6, 7</sup>
- Drive FPGA into reset<sup>7</sup>



FPGA voltage sensors surrounding RSA core<sup>1</sup>

<sup>1</sup> Zhao and Kuh, FPGA-Based Remote Power Side-Channel Attacks, IEEE Symp. Security and Privacy, May 2018

<sup>2</sup> Schellenberg et al, An Inside Job: Remote Power Analysis Attacks on FPGAs, DATE, March 2018

<sup>3</sup> Gnad et al, "Voltage-based covert channels in multi-tenant FPGAs," Cryptology ePrint Archive, vol. Report 2019/1394, 2019

<sup>4</sup> Giechaskiel et al., "Reading between the dies: Cross-SLR covert channels on multi-tenant cloud FPGAs" ICCD, Oct. 2019

<sup>5</sup> Krautter et al, FPGAhammer: Remote Voltage Fault Attacks on Shared FPGAs, suitable for DFA on AES, CHES, vol 3 , 2018

<sup>6</sup> Mahmoud and Stojilovic, "Timing violation induced faults in multi-tenant FPGAs," in DATE 2019

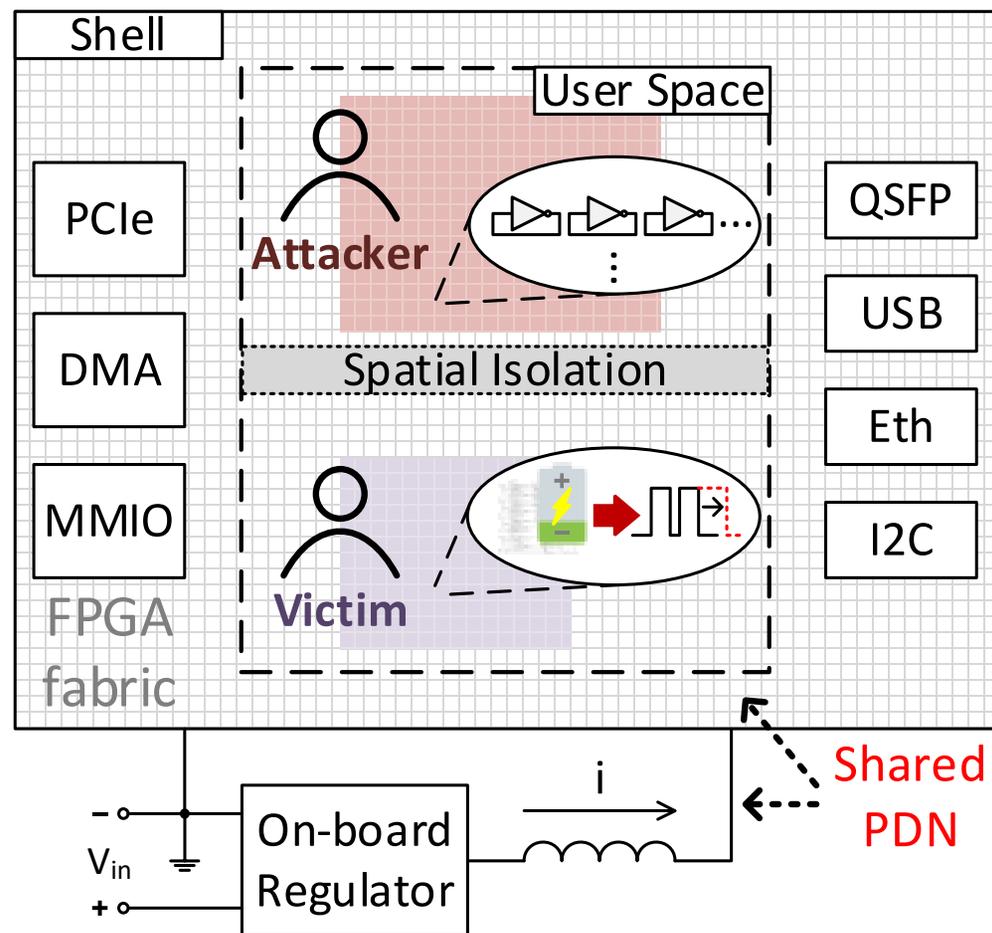
<sup>7</sup> Provelengios, "Characterizing Power Distribution Attacks in Multi-User FPGA Environments", FPL 2019

# Overview

- Two tenants are using simultaneously the device
- Tenant A (**attacker**) consumes power aggressively in an attempt to induce timing faults in tenant B (**victim**)

## Threat model:

- ✓ Tenants are spatially isolated but share the FPGA power distribution network (PDN)
- ✓ Tenants do not have physical access to the board
- ✓ The tools used for interacting with the FPGA are secure



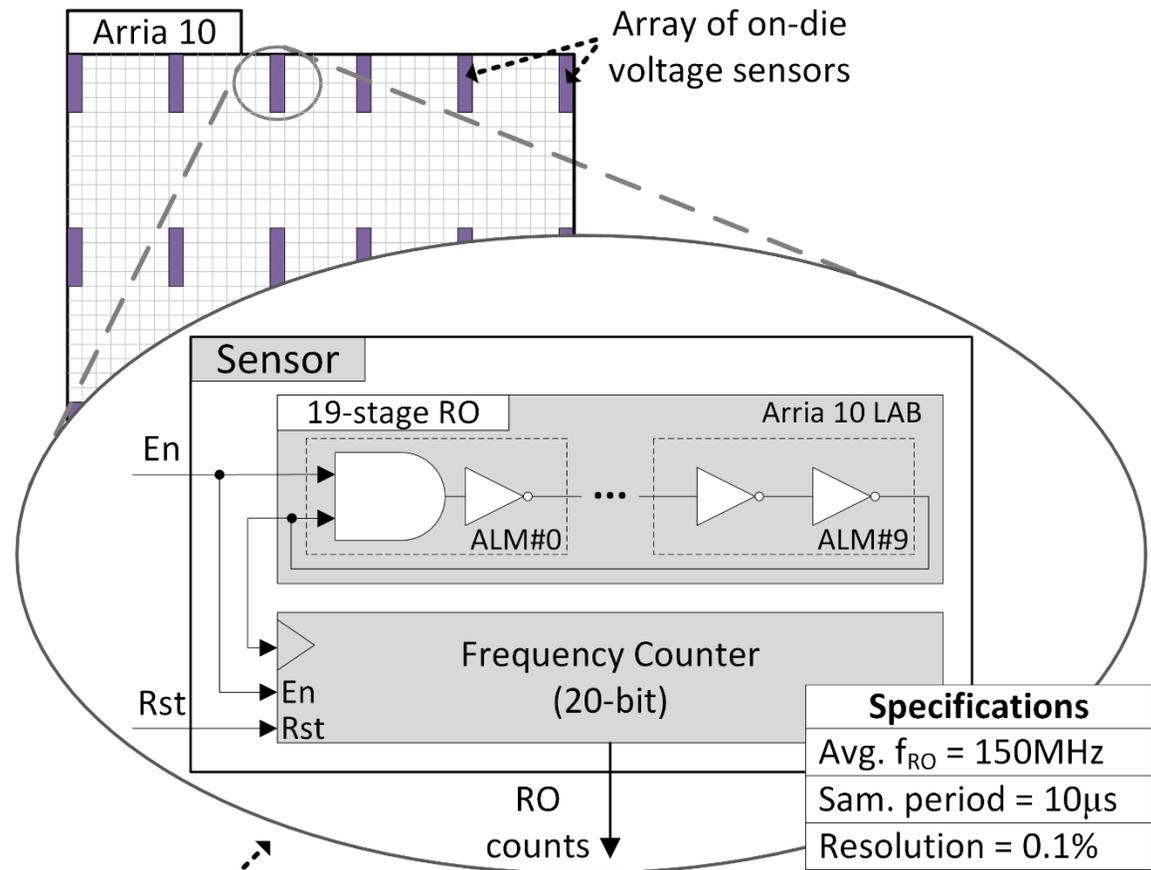
## Contribution

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- We investigate on-chip voltage attacks and specifically how their impact depends on:
  - Duration of voltage disruption
  - Consumed power by attacker
  - Distance between attacker & victim
- We evaluate the ability of power wasting circuits to induce timing faults to victim
- We examine the ability of power wasting circuits to reveal an RSA encryption key through fault injection

# Voltage sensor architecture

- A regular rectangular grid of 46 sensors
- 19 inverting stages:
  - ✓ Meet timing constraints
  - ✓ Minimize local effects<sup>1</sup>
  - ✓ Fit in a single CV LAB
- Arria 10 parameters
  - $f_{RO} = 150$  MHz
  - Samp. period =  $10\mu\text{s}$

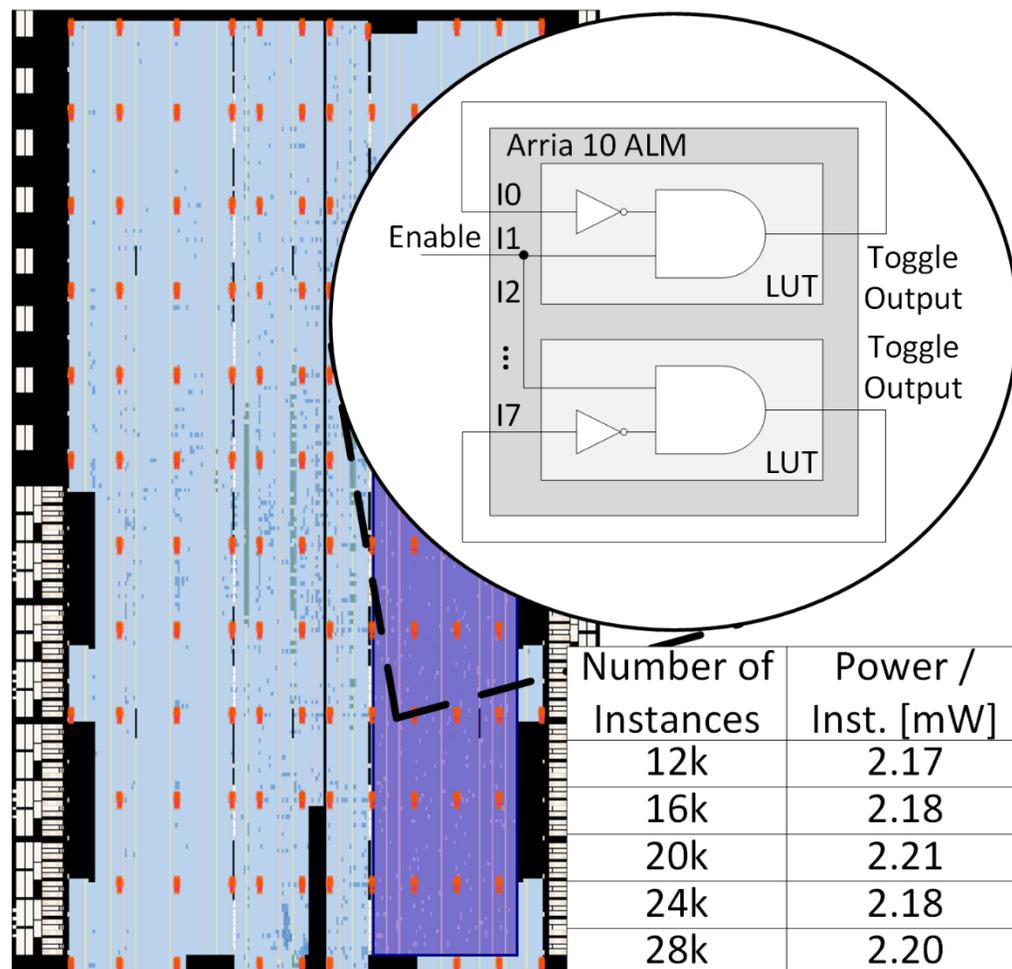


Controller reads and resets all the sensors simultaneously in every sampling period

<sup>1</sup> M. Barbareschi, G. Di Natale, and L. Torres, "Implementation and analysis of ring oscillator circuits on Xilinx FPGAs," in *Hardware Security and Trust*. N. Sklavos, R. Chaves, G. Di Natale, and F. Regazzoni, Eds. Springer, 2017, ch. 12, pp. 237-251

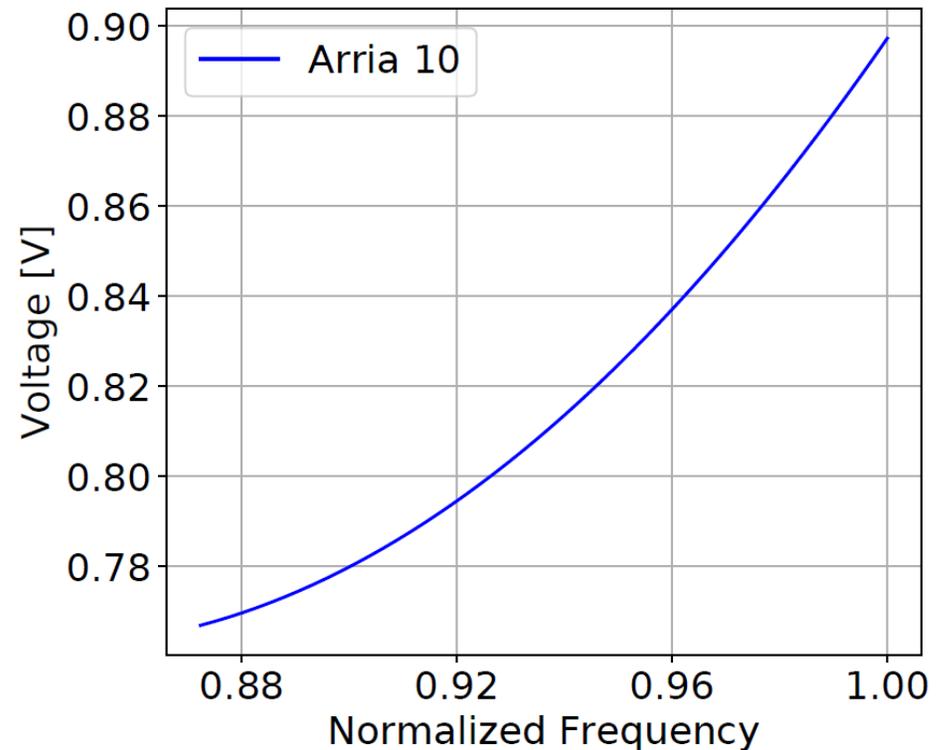
# Attacker circuitry

- $P_{dyn} = C \times V_{DD}^2 \times f_{sw}$
- 1-stage ROs as power wasters
- Arria 10: 11,424 LABs fit up to 28K PW
- Placed uniformly at random locations in the attack area



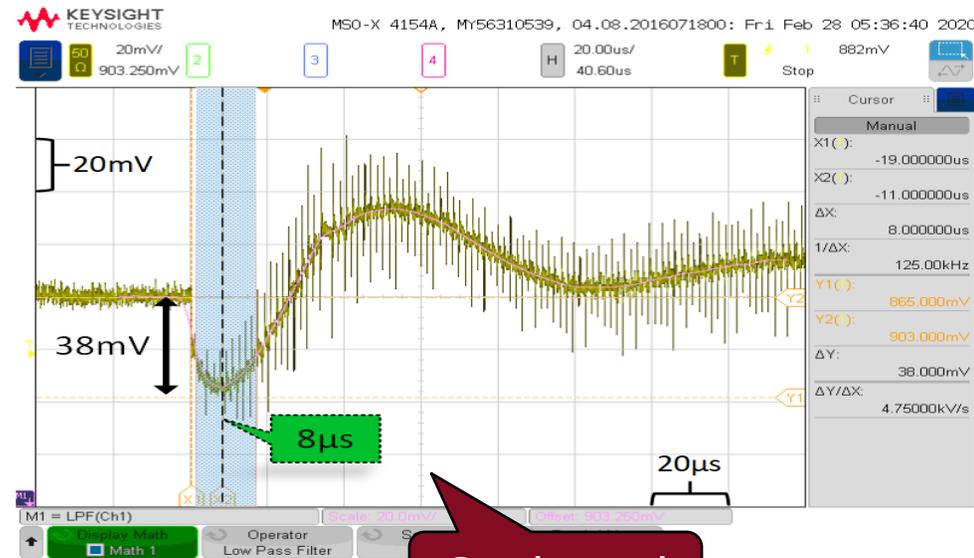
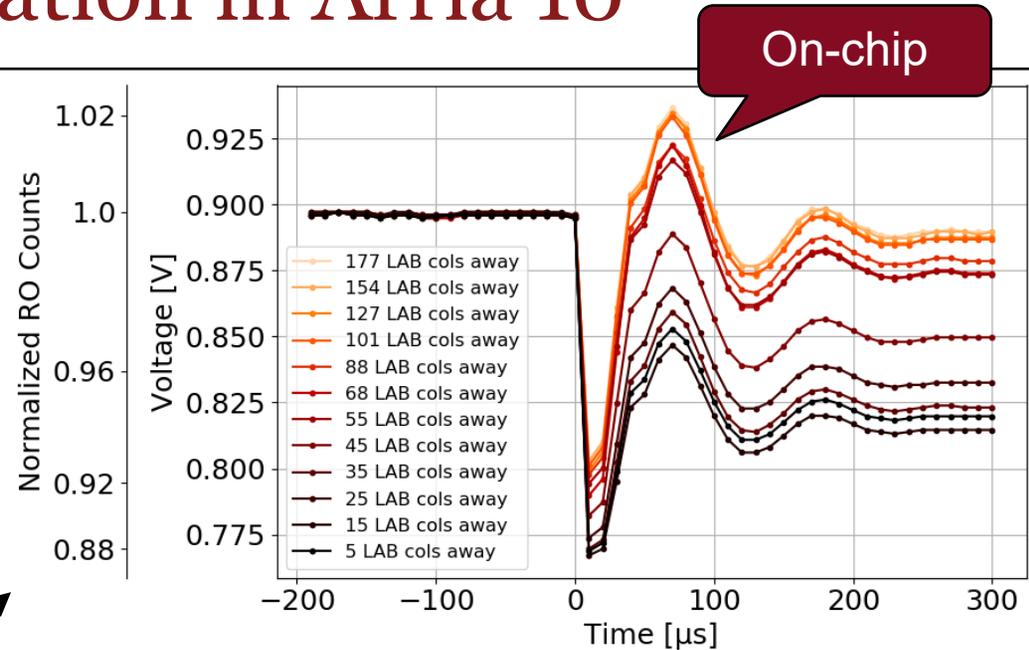
# Arria 10 sensor calibration

- To use ROs as on-chip voltage sensors:
  - Vary power waster count between 8,000 and 28,000 and record:
    - ✓ Voltage on on-chip sensor
    - ✓ RO counts from on-chip sensors
- Minimize the power drawn by the FPGA during measurements



# Voltage drop characterization in Arria 10

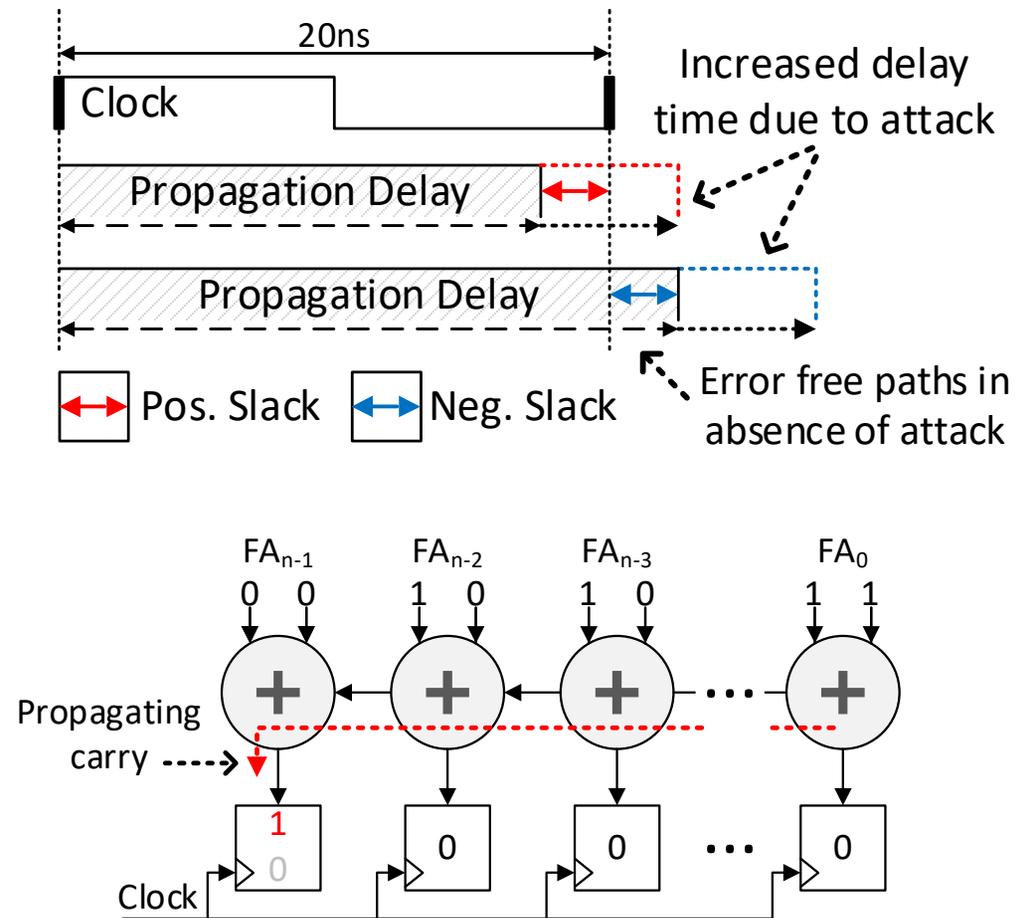
- Evaluate the Arria 10 PDN response
- 28k RO-based PW instances
- 12 on-chip sensors at different distances to the center of the waster
- Peak voltage drop  $\sim 8\mu s$  after activating PWs



On-board

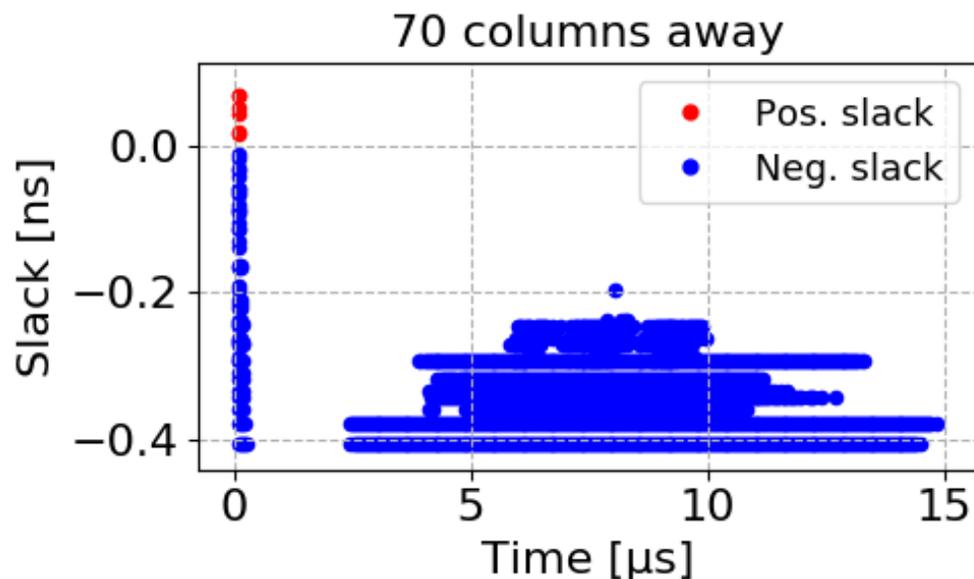
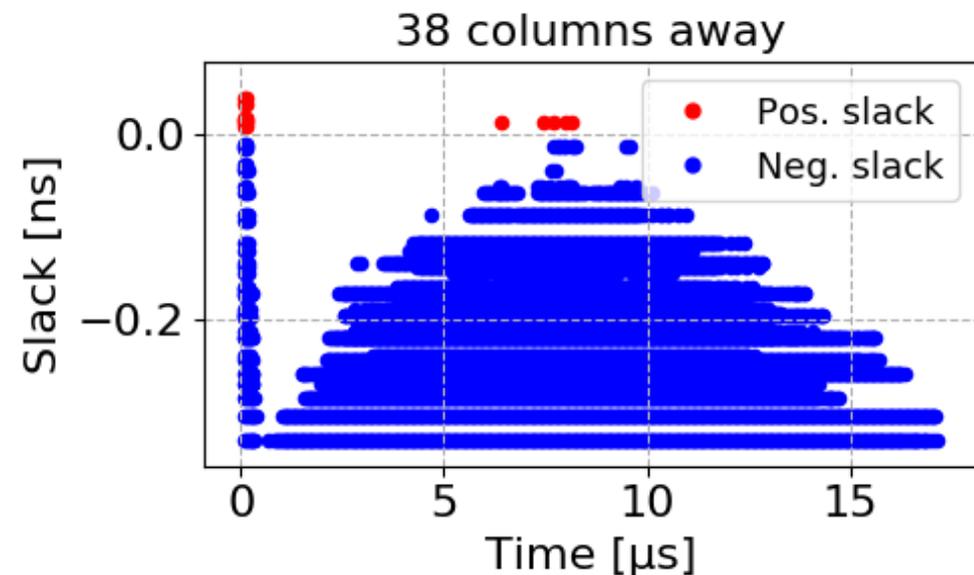
# Characterizing timing faults

- Voltage drop causes delay of combinational logic to increase
- Wrong values captured if paths do not complete before capturing clock edge arrives
- Must overcome conservative timing models
- Use ripple carry adder as a representative test circuit which allows us to sensitize various path lengths



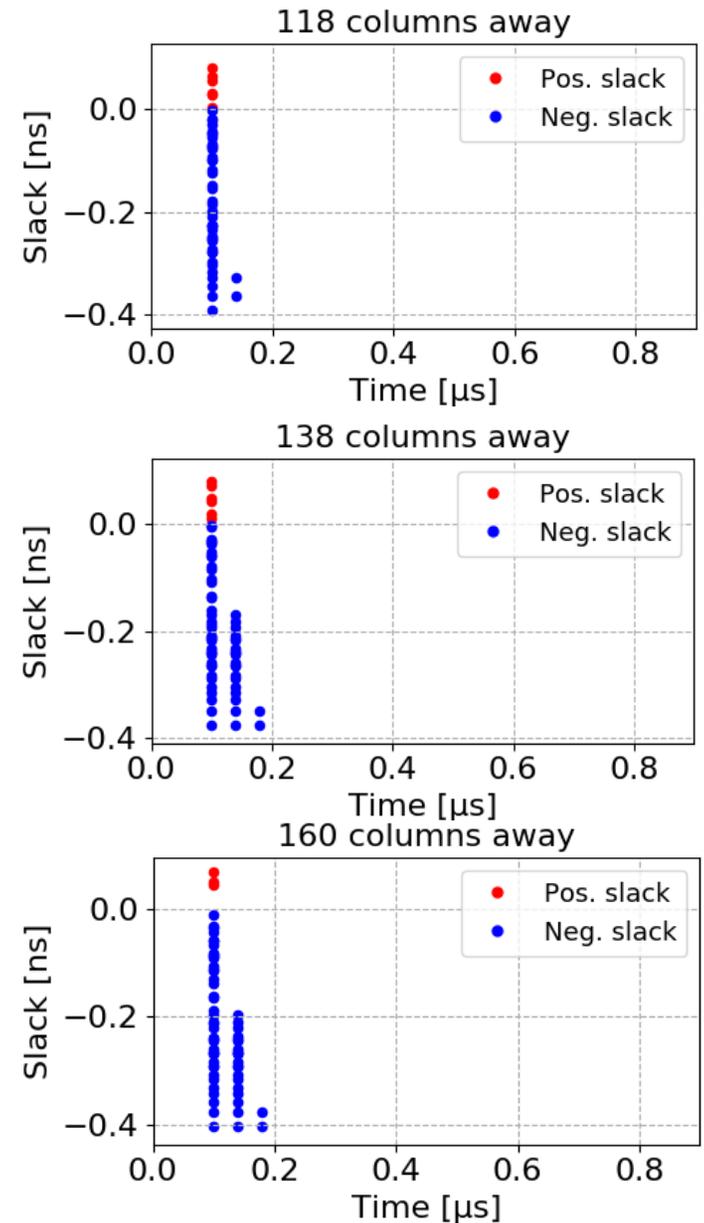
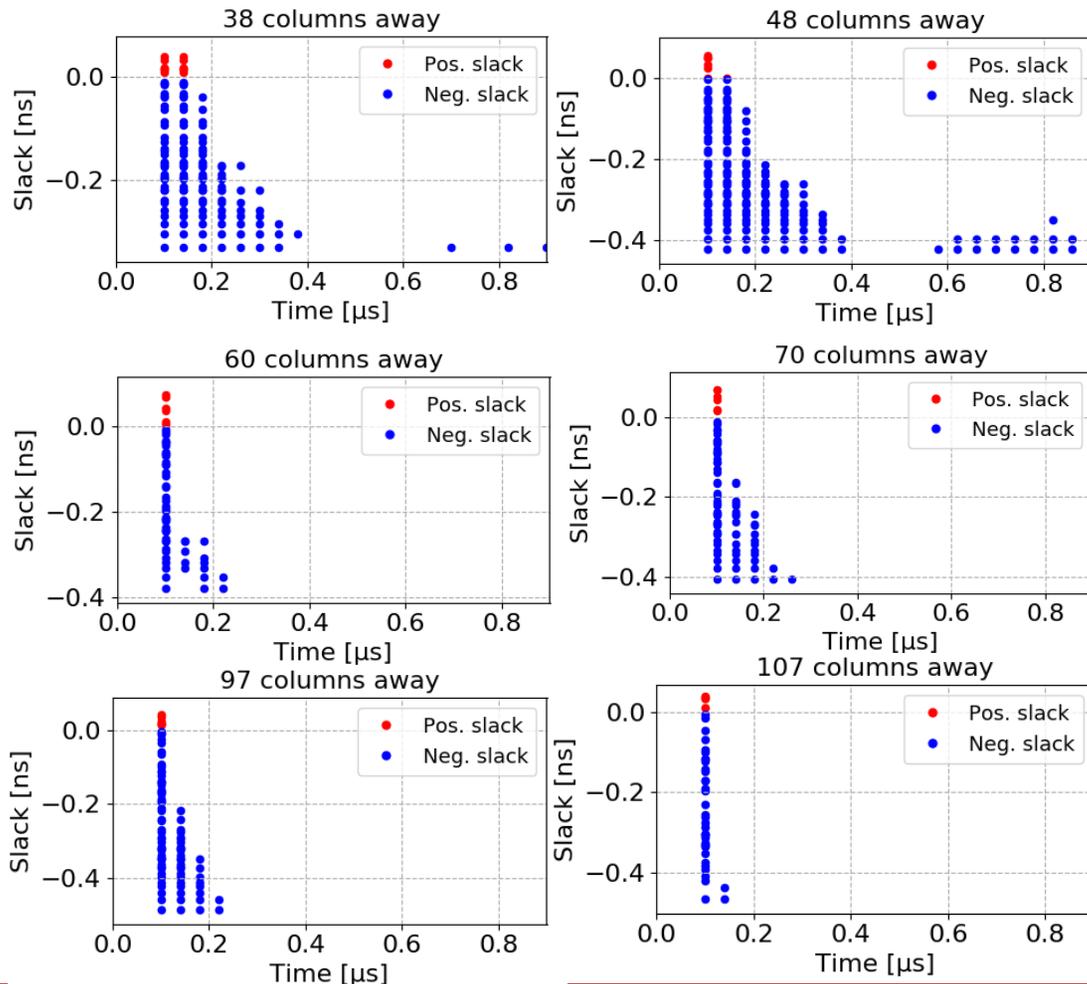
# Arria 10 timing faults

- 28k PWs randomly placed in an area of 11,424 LABs (168x68)
- Steep voltage drop at 20 ns induces faults
- Faults peak at 8  $\mu$ s
- Substantially fewer faults than Cyclone V



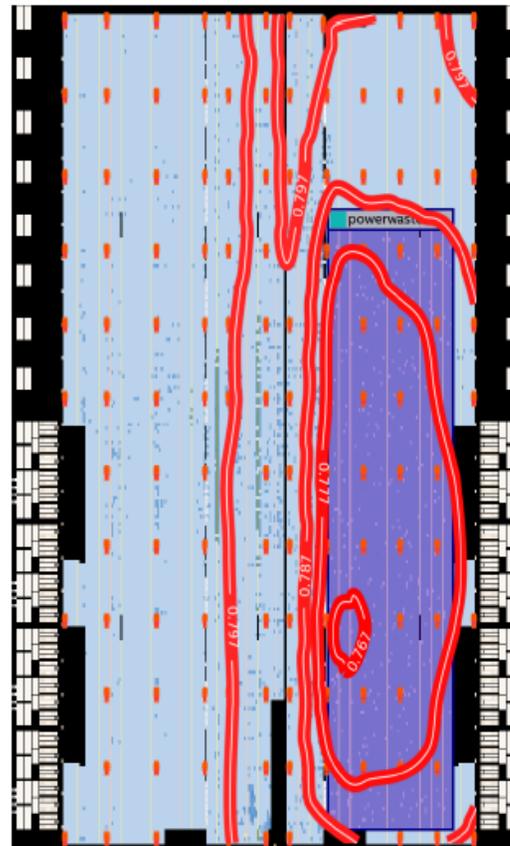
# Can a victim evade the attack?

- In Arria 10, the initial fast voltage drop is not location dependent
- Faults from legal paths reported even at the edge of the device

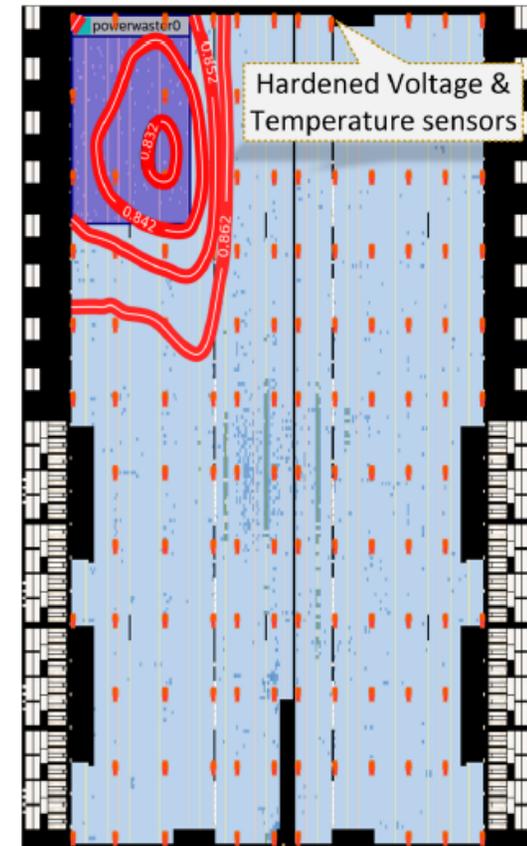


# Mapping the Arria 10 voltage drop

- Using 132 on-chip sensors for deriving the voltage contours
- Varying the magnitude of disturbance and location of attacker
- Center of attack:
  - 28K PWs: 767mV
  - 8K PWs: 862mV
- Upper right corner of the chip:
  - 28K PWs: 797mV



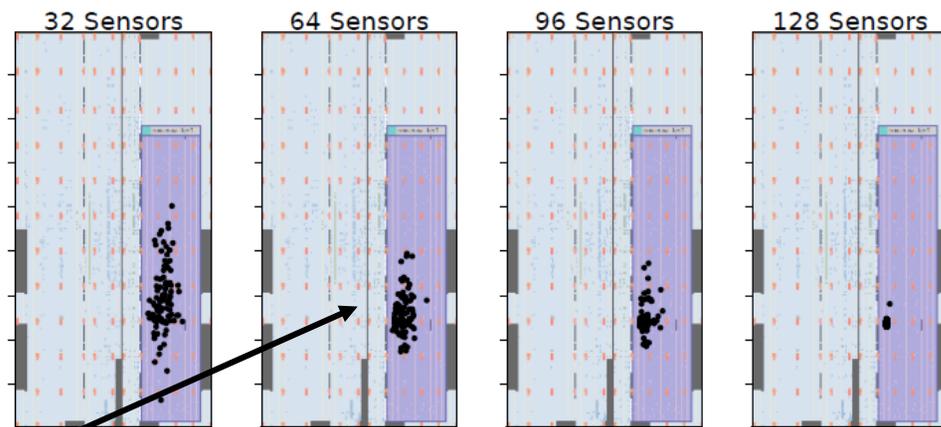
(A) 28K power waster attack



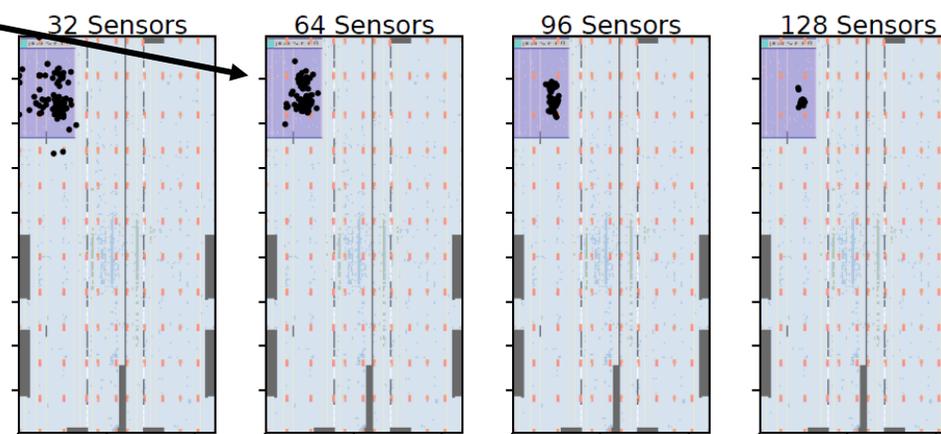
(B) 8K power waster attack

# Locating the Arria 10 attack area

- The disturbance of the shared PDN reveals the location of the attacker
- Evaluate how many sensors required to find its location
- 64 sensors are sufficient to identify the attacker



(A) 28K power waster attack

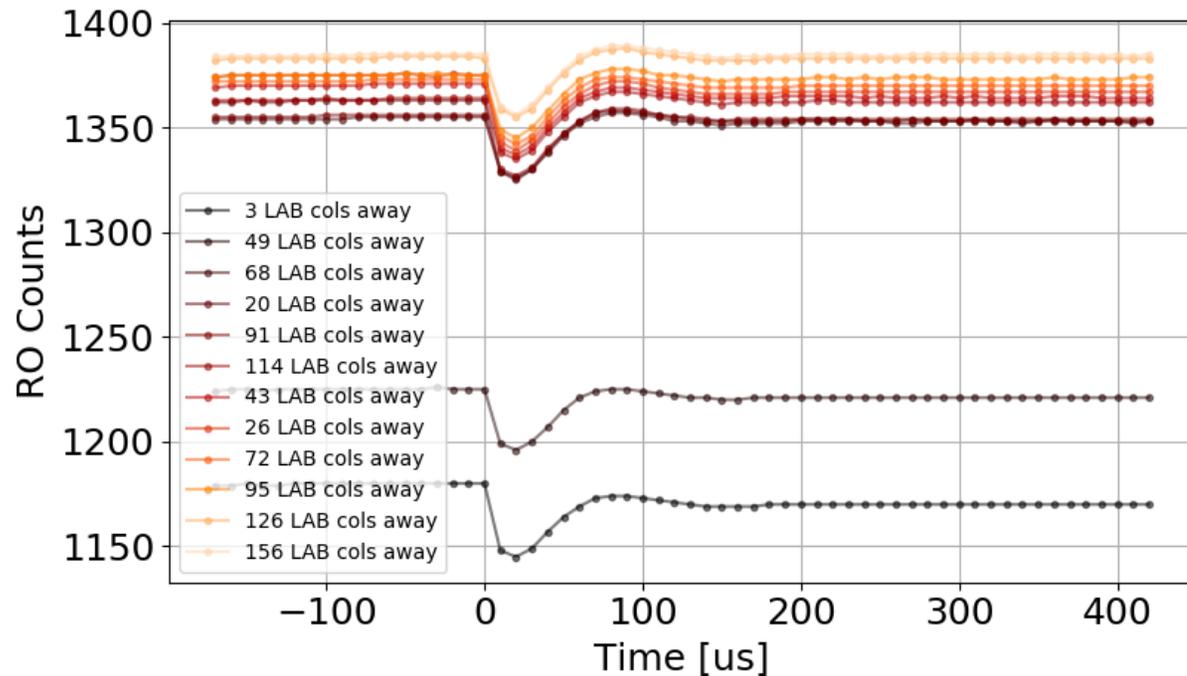


(B) 8K power waster attack

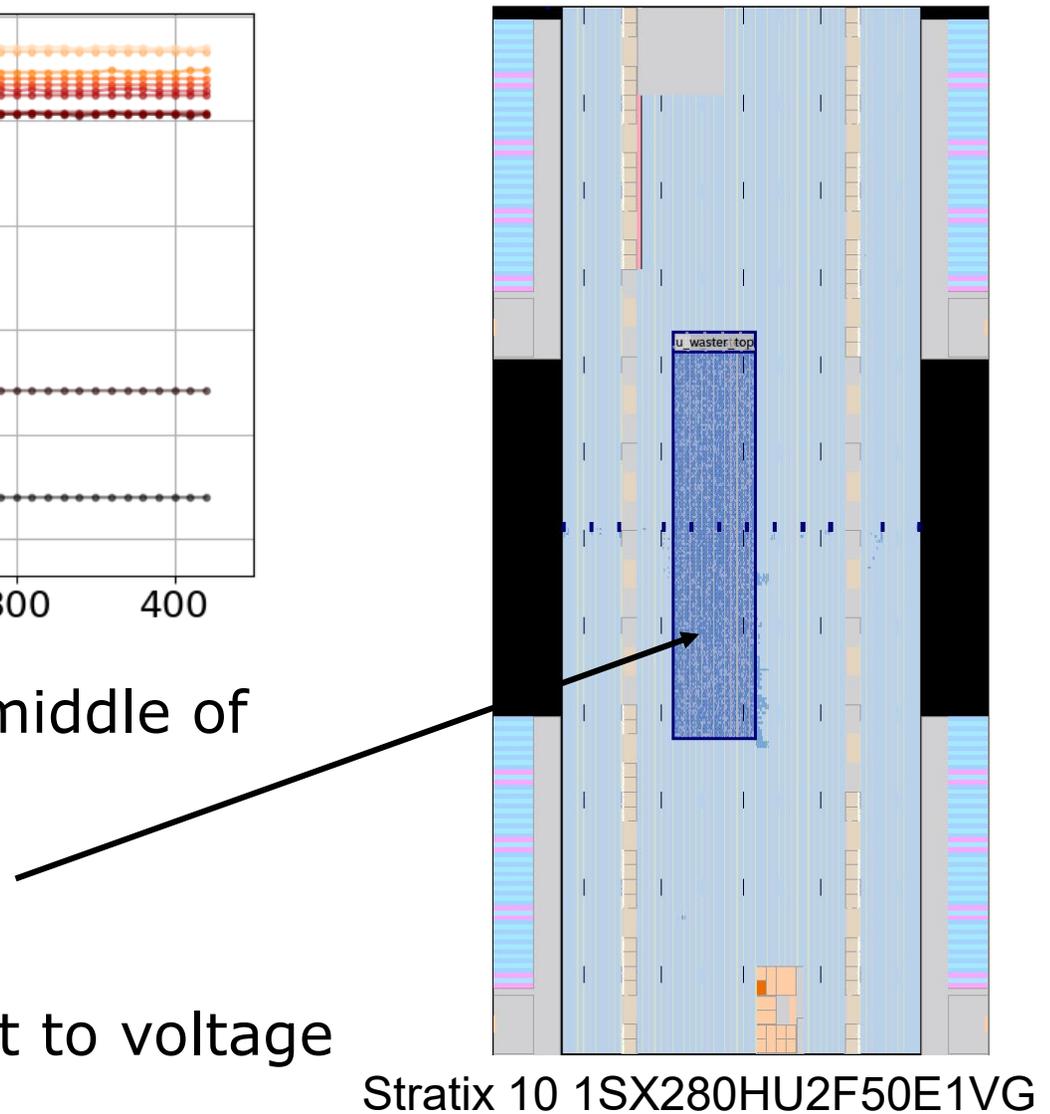
Resource utilize.: Arria 10AX115N2F45E1SG

Num. RO Sensors	ALMs (Avail.: 427,200)	Flip-flops (Avail.: 1,708,800)
64	1,280 (<1%)	1,280 (<1%)
132	2,640 (<1%)	2,640 (<1%)
Controller	1,008 (<1%)	134 (<1%)

# Preliminary Results with Stratix 10 on DE10-Pro



- 12 ring oscillators located in middle of device
- 10,000 power wasters
- Sampling period of 10  $\mu$ s
- Ongoing: translating RO count to voltage



# Attacking RSA through fault injection

- Exploiting the use of the Chinese Remainder Theorem (CRT) <sup>1</sup>:

Direct RSA	RSA with CRT (4x faster)
$Y = X^e \text{ mod } N$	$Y = aY_1 + bY_2$ $Y_1 = (X \text{ mod } p)^{e \text{ mod } (p-1)} \text{ mod } p$ $Y_2 = (X \text{ mod } q)^{e \text{ mod } (q-1)} \text{ mod } q$

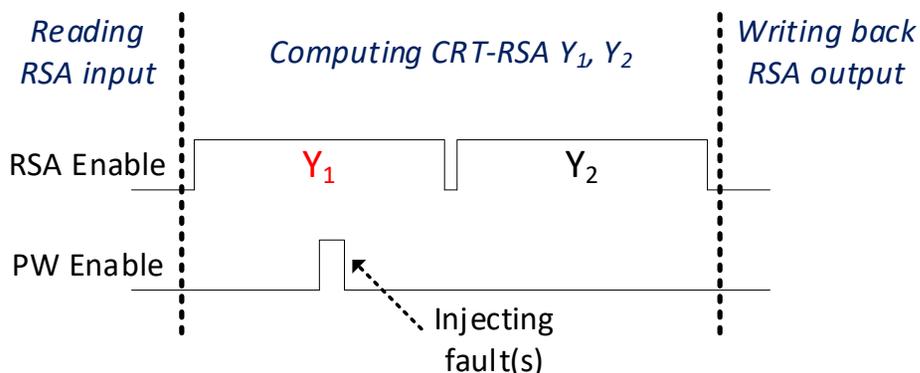
X, Y	Input, Output
e	Priv. key exponent
N	n-bit Modulus
p, q	n/2-bit Primes
a, b	Constants

- Goal:** Inject fault(s) while computing  $Y_1$  or  $Y_2$

- Fault during CRT reveals key

- Output  $Y$  is assembled with a faulty  $Y_1$
- Prime number  $q$  is revealed
- Private key  $e$  can be reconstructed
- $e$  can also be extracted with a faulty  $Y_2$

- The attack works for any key length
- A single interaction is sufficient <sup>2</sup>

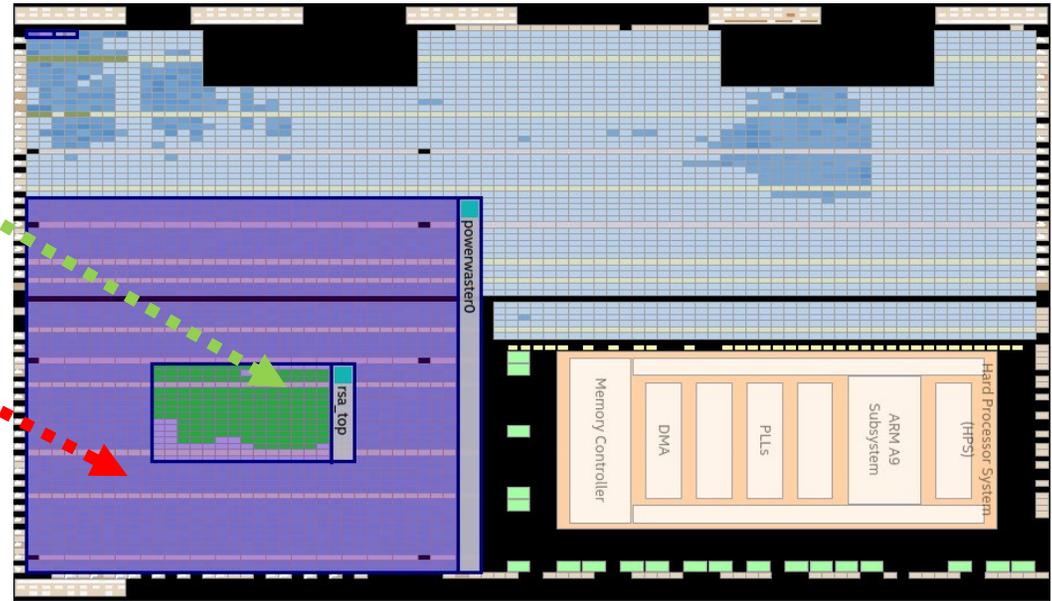


<sup>1</sup> D. Boneh et al., On the Importance of Eliminating Errors in Cryptographic Computations, Journal of Cryptology, 2001

<sup>2</sup> A.K Lenstra, Memo on RSA signature generation in the presence of faults, 1996

## RSA experimental setup

- 128-bit RSA implementation is placed in an area of 256 LABs
- Wasters are placed at random locations around the RSA core covering an area of 1,940 LABs
- A script running on host PC is responsible for controlling the experiment



(Quartus Prime 17.1 - ChipPlanner)

Resource utilization: Cyclone V 5CSEMA5F31C6

RSA core	ALMs (Avail.: 32,070)	Flip-flops (Avail.: 128,280)	Memory [Kb] (Avail.: 3,970 Kb)	F <sub>max</sub> [MHz]
128-bit	1,236 (3.9%)	1,925 (1.5%)	16	94.74

# Extracting the RSA private key

```

lab@lab:~/project/$ make rsa_attack B=builds/build_2020-02-15_04-48-53
Resetting RSA core and setting test parameters ...
Starting experiment ...
Turn on 10900 wasters at time 0.00000183
Waiting for 1 seconds ... 1, done
[mif_parser] parsing extracted MIF and dumping to file(s) ... done
Retrieving Y1 and Y2 RSA outputs ... done
***** Test Completed *****
RSA test      : FAIL
Key length    : 128 bit
RSA core output: 0x35f3ad9c676ffcedbd2b5d621ed718b9
Expected output: 0x34bc3c6b59eaf60fcb488411e3fdbae2

[extract_rsakey] RSA output: 0x35f3ad9c676ffcedbd2b5d621ed718b9

[extract_rsakey] Extract the first prime number using the faulty
output (p1 = gcd(x - y^pub_exp, N)):
p1 = 0x8cabce4e903ea111

[extract_rsakey] Factor modulus N (p2 = N/p1) to get the second prime number:
p2 = 0xdb53798e1cb036bd

[extract_rsakey] Calculate phi ((p1-1)*(p2-1)):
phi = 0x7884d7fc6471889a7e87ffab9ef7a7c0

[extract_rsakey] Calculate the priv. exponent (pr exp = (1/pub_exp) mod phi):
Extracted priv. exponent = 0x710c43115c59495105ea53342309a0a9

[extra Original key: 0x710c43115c59495105ea53342309a0a9
[extract_rsakey] ... done. Elapsed time is 0:00:00.000702
lab@lab:~/project/$

```

timing fault(s)  
occurred!

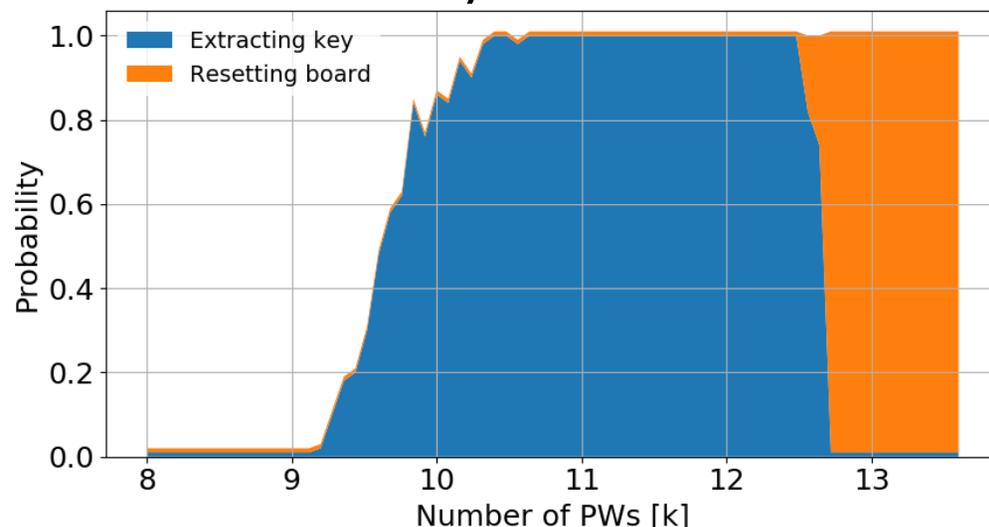
- Hardware computes  $Y_1$  and  $Y_2$  while wasters are turned on
- Reading out  $Y_1$ ,  $Y_2$  and assembling final output  $Y$
- $Y$  does not match the expected output
- Extract the first prime
- Factor  $N$  to get the second prime
- Reconstruct the private exponent
- ✓ Extracted and original keys match

## How many wasters are required?

- Vary the number of wasters and find the probability of extracting the key
- Cyclone V:
  - 11K-12K PWs: high chance of extracting the key undetected
  - $F_{\max}$ : 94.74MHz,  $F_{\text{break}}$ : 166MHz (w/o wasters)

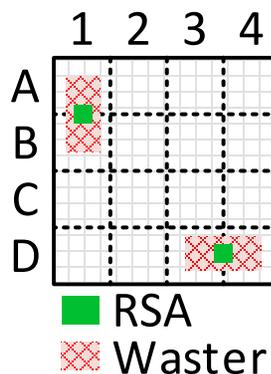
~4.5ns margin!

### Cyclone V



- Identifying weak spots in Arria 10 based on:
  - Number of PWs that can safely be activated
  - Yield in less timing margin

work in progress



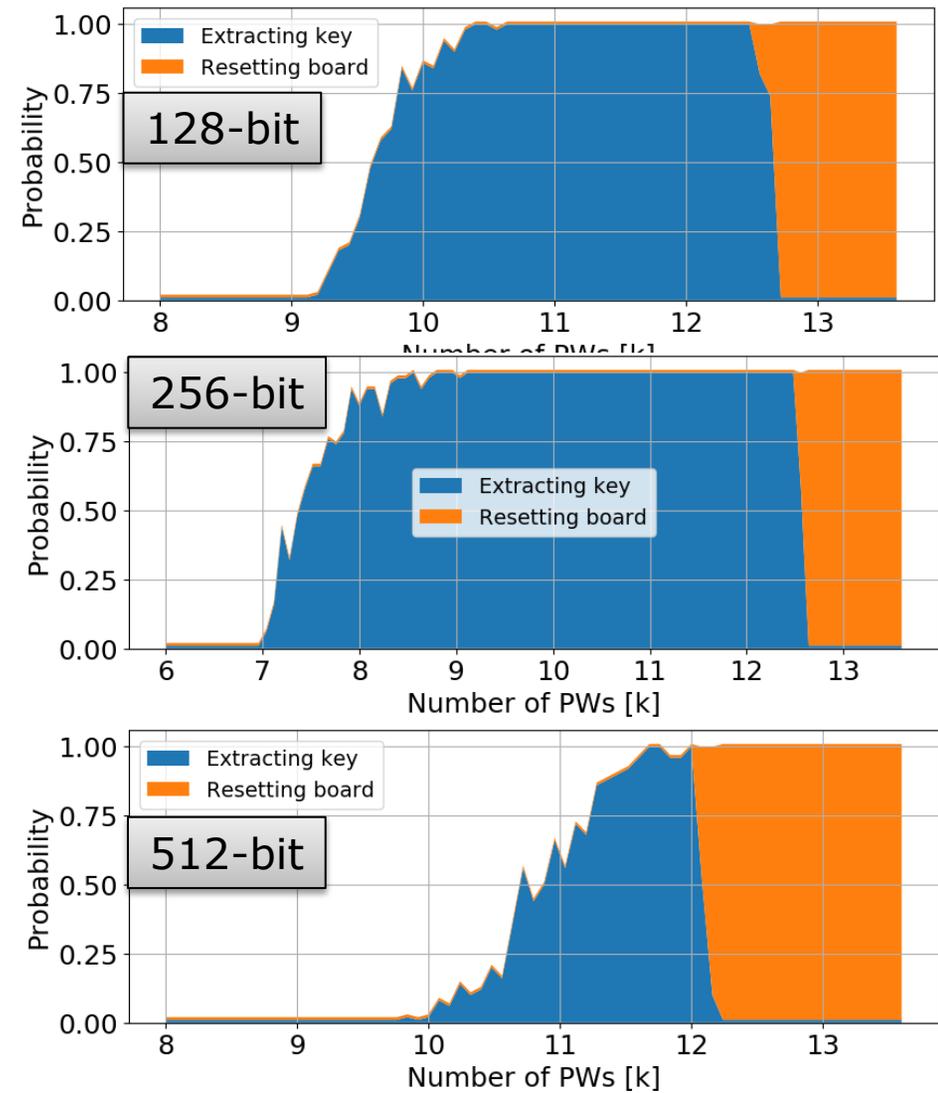
### Arria 10

Loc.	PWs [k]	$F_{\max}$ [MHz]	$F_{\text{break}}$ [MHz] (w/ wasters)	$F_{\text{break}}$ [MHz] (w/o wasters)
A1, B1	20	179	250	270
A1, B1	24	162	262	281
A1, B1	28	165	240	268
D3, D4	30	103	123	137

# How many wasters are required? (cont'd)

- Vary the number of wasters and find the probability of extracting the key
- 11K-12K PWs: high chance of extracting the key undetected
- $F_{\max}$ : 94.74MHz,  $F_{\text{break}}$ : 166MHz (w/o wasters)

~4.5ns  
margin!



# Summary

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- Multi-tenant FPGAs
  - Logical next step for cloud computing
  
- Voltage based attacks
  - Easy to create power wasting circuits that induce faults or crash FPGA
  
- Characterizing voltage attacks on Arria 10
  - 15% core voltage drop within 8 us
  - Induces faults throughout device
  
- RSA attack
  - Single fault sufficient to expose key
  - Effective for Cyclone V (even defeats built in timing margin)
  - Effective for Arria 10 if design is overclocked